International Rectifier

IRF2805PbF

HEXFET® Power MOSFET

Typical Applications

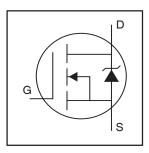
Industrial Motor Drive

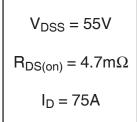
Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

Description

This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon limited)	175	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (See Fig.9)	120	Α
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package limited)	75	
I _{DM}	Pulsed Drain Current ①	700	
P _D @T _C = 25°C	Power Dissipation	330	W
	Linear Derating Factor	2.2	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy②	450	mJ
E _{AS} (6 sigma)	Single Pulse Avalanche Energy Tested Value [®]	1220	1
I _{AR}	Avalanche Current①	See Fig.12a, 12b, 15, 16	Α
E _{AR}	Repetitive Avalanche Energy®		mJ
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	1.1 (10)	N•m (lbf•in)

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.45	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$	
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.06		V/°C	Reference to 25°C, I _D = 1mA	
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.9	4.7	mΩ	V _{GS} = 10V, I _D = 104A ④	
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = 10V, I_D = 250\mu A$	
9 fs	Forward Transconductance	91			S	V _{DS} = 25V, I _D = 104A	
	Drain-to-Source Leakage Current			20	μA	V _{DS} = 55V, V _{GS} = 0V	
I _{DSS}				250	μΛ	$V_{DS} = 55V$, $V_{GS} = 0V$, $T_{J} = 125$ °C	
	Gate-to-Source Forward Leakage			200	nA	V _{GS} = 20V	
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V	
Qg	Total Gate Charge		150	230		I _D = 104A	
Q _{gs}	Gate-to-Source Charge		38	57	nC	$V_{DS} = 44V$	
Q _{gd}	Gate-to-Drain ("Miller") Charge		52	78		V _{GS} = 10V ⊕	
t _{d(on)}	Turn-On Delay Time		14			V _{DD} = 28V	
t _r	Rise Time		120			$I_D = 104A$	
t _{d(off)}	Turn-Off Delay Time		68		ns	$R_G = 2.5\Omega$	
t _f	Fall Time		110			V _{GS} = 10V ⊕	
	Internal Drain Inductance		4.5			Between lead,	
L _D	Internal Drain Inductance		4.5		nH	6mm (0.25in.)	
	lateral Comments to the second						from package
L _S	Internal Source Inductance		7.5			and center of die contact	
C _{iss}	Input Capacitance		5110			V _{GS} = 0V	
C _{oss}	Output Capacitance		1190		pF	$V_{DS} = 25V$	
C _{rss}	Reverse Transfer Capacitance		210			f = 1.0MHz, See Fig. 5	
Coss	Output Capacitance		6470		1	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$	
Coss	Output Capacitance		860		1	$V_{GS} = 0V, V_{DS} = 44V, f = 1.0MHz$	
Coss eff.	Effective Output Capacitance ⑤		1600]	V _{GS} = 0V, V _{DS} = 0V to 44V	

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current	1		175		MOSFET symbol			
	(Body Diode)		1/5	A	showing the				
I _{SM}	Pulsed Source Current				700	700	700		integral reverse
	(Body Diode) ①			700		p-n junction diode.			
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 104A$, $V_{GS} = 0V$ ④			
t _{rr}	Reverse Recovery Time	Ī	80	120	ns	$T_J = 25^{\circ}C, I_F = 104A$			
Q _{rr}	Reverse Recovery Charge	I	290	430	nC	di/dt = 100A/µs ④			
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)							

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Starting $T_J = 25^{\circ}\text{C}$, L = 0.08mH $R_G = 25\Omega$, $I_{AS} = 104\text{A}$. (See Figure 12).
- $\label{eq:loss} \begin{array}{l} \text{ } \\ \text{ }$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- $\ \ \, \ \, \ \,$ $\ \ \, \ \,$ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.

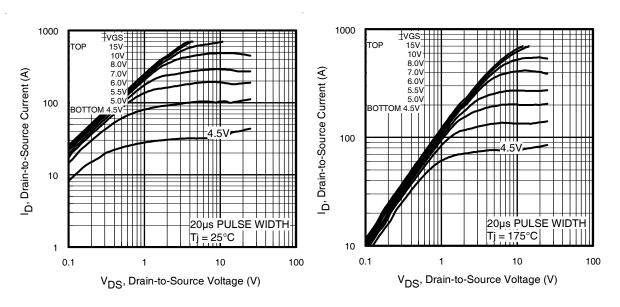


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

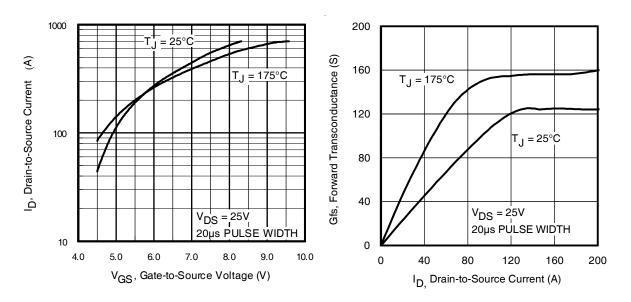


Fig 3. Typical Transfer Characteristics

Fig 4. Typical Forward Transconductance Vs. Drain Current

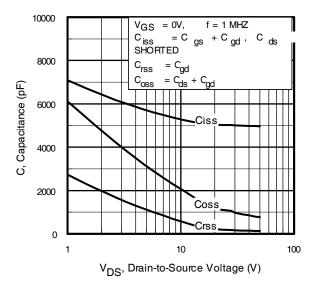


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

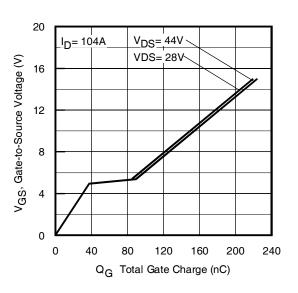


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

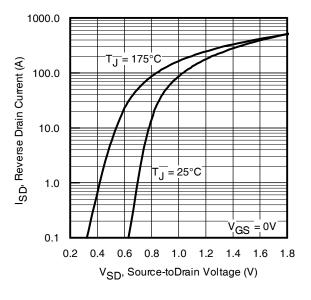


Fig 7. Typical Source-Drain Diode Forward Voltage

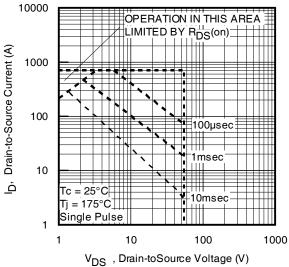
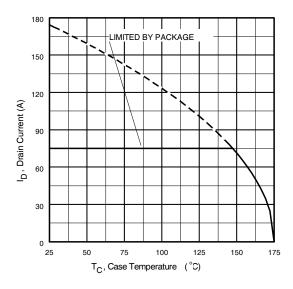


Fig 8. Maximum Safe Operating Area



I_D = 175A 2.5 $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize on})}$, Drain-to-Source On Resistance 2.0 (Normalized) 1.5 1.0 0.5 120 140 160 180 -60 0 20 40 60 80 100 $\mathbf{T_{J}}, \mathbf{Junction\ Temperature}$ (° C)

Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

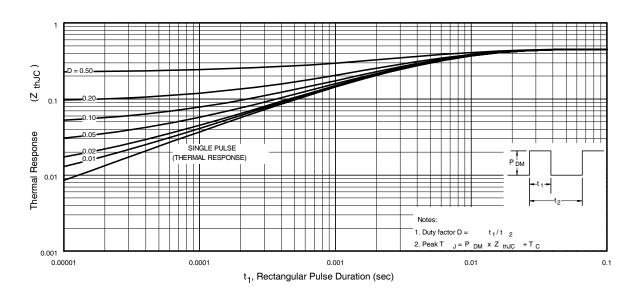


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

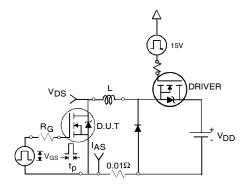


Fig 12a. Unclamped Inductive Test Circuit

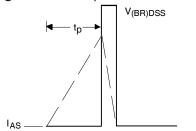


Fig 12b. | Unclamped Inductive Waveforms

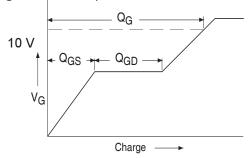


Fig 13a. Basic Gate Charge Waveform

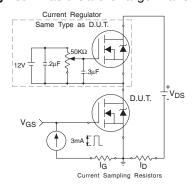


Fig 13b. Gate Charge Test Circuit 6

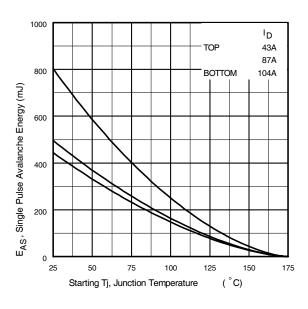


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

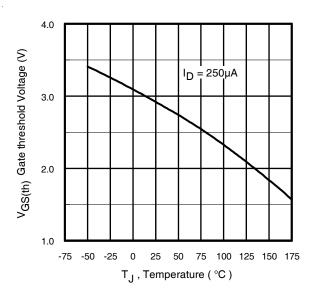


Fig 14. Threshold Voltage Vs. Temperature www.irf.com

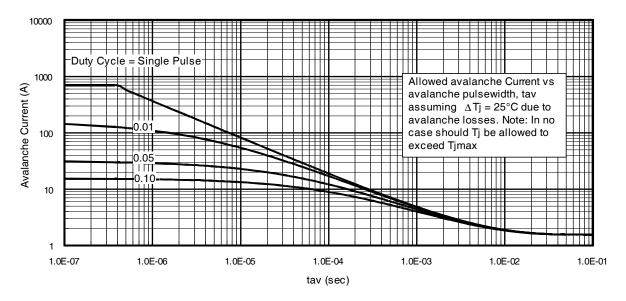


Fig 15. Typical Avalanche Current Vs.Pulsewidth

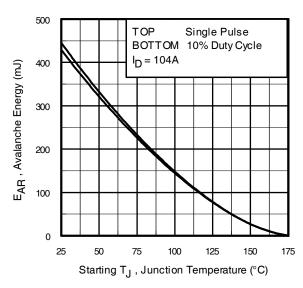


Fig 16. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{imax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

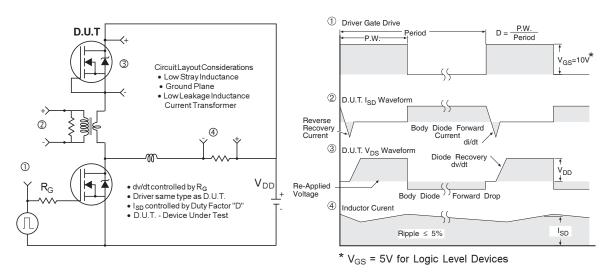


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

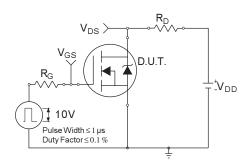


Fig 18a. Switching Time Test Circuit

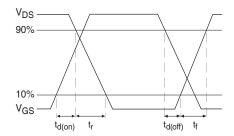
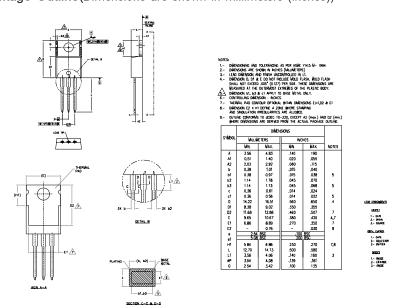
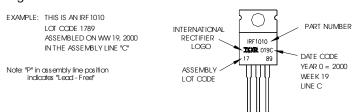


Fig 18b. Switching Time Waveforms

TO-220AB Package Outline(Dimensions are shown in millimeters (inches))



TO-220AB Part Marking Information



TO-220AB package is not recommended for Surface Mount Application.

Notes:

- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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